

<b>Notice of References Cited</b>	Application/Control No. 09/916,517	Applicant(s)/Patent Under Reexamination LEE, TAE WON	
	Examiner Trang U. Tran	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,229,480 B1	05-2001	Shintani, Peter Rae	342/359
*	B	US-6,049,361 A	04-2000	Kim, Ki-bum	348/678
*	C	US-5,638,140	06-1997	Krishnamurthy et al.	348/735
*	D	US-6,697,610 B1	02-2004	Tait, David S.	455/277.1
*	E	US-6,509,934 B1	01-2003	Bao et al.	348/570
*	F	US-6,661,373 B1	12-2003	Holliday, David	342/359
*	G	US-6,334,218 B1	12-2001	Jeong et al.	725/72
*	H	US-5,515,058 A	05-1996	Chaney et al.	342/359
*	I	US-5,376,941 A	12-1994	Fukazawa et al.	342/359
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.